

Notice of References Cited	Application/Control No. 10/534,069		Applicant(s)/Patent Under Reexamination IIMORI, YASUO	
	Examiner Russell Frejd		Art Unit 2128	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,961,683	11-2005	Kodama et al.	703/2
*	B	US-6,839,642	01-2005	Kawakita et al.	702/42
*	C	US-6,439,059	08-2002	Inoue et al.	73/812
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	FOX et al., A. The Effect of Gold-Tin Intermetallic Compound on the Low Cycle Fatigue Behavior of Copper Alloy C72700 and C17200 Wires, IEEE Transactions on Components, Hybrids, and Manufacturing Technology, Vol. CHMT-9, No. 3, September 1986, pp. 272-8.
	V	MIYAZAKI et al., S. Fatigue life of Ti-50 at.% Ni and Ti-40Ni-10Cu (at.%) shape memory alloy wires, Materials, Science and Engineering, Vol. 273-275, December 1999, pp. 658-663.
	W	ZHOU et al., Z.R. Single wire fretting fatigue tests for electrical conductor bending fatigue evaluation, Wear, Vol. 181-183, March 1995, pp. 537-43.
	X	CHIANG, Y.J. Characterizing simple-stranded wire cables under axial loading, Finite Elements in Analysis and Design, Vol. 24, December 1996, pp. 49-66.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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